



Europass Curriculum Vitae

Personal information

First name / Surname **Luca FALZONI**
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LinkedIn profile <https://www.linkedin.com/in/lucafalzoni/>
Nationality Italian
Date of birth 24.03.1970

Desired field **Technical/scientific translator from English and German into Italian**

Work experience

Dates **April 2018 onwards (current position)**

Occupation or position held Senior Expert Component Verification, IPC Group (Industrial & Power Conversion)
Main activities and responsibilities Characterization of high-voltage components for industrial applications in cooperation with other company sites in Austria, Germany and the USA, managing of the IPC characterization laboratory
Name and address of employer Infineon Technologies Italia S.r.l., Pavia (Italy)
Type of business or sector Semiconductors

Dates **November 2014 to February 2018**

Occupation or position held Quality engineer FA, Chip Development Project Manager
Main activities and responsibilities - As quality engineer: failure analysis of customer returns (power products and Hall sensors for the automotive market)
- As project manager: coordination of the concept and design phase of automotive products and of the production of test chips for prequalification purposes, project risk evaluation and customer sampling
Name and address of employer Infineon Technologies Austria AG, Villach (Austria)
Type of business or sector Semiconductors

Dates **April 1999 – September 2014**

Occupation or position held Project Manager, Product Engineer, Analog IC Designer
Main activities and responsibilities - As product engineer: management of a MEMS characterization lab
- As project manager: planning and coordination of the industrialization of MEMS environmental and inertial sensors, DC motor and head drivers and digital SoC for printers, from first silicon to production
- As analog IC designer: design of DC motor and head drivers for printers according to customer specifications, laboratory characterization of devices performance and functionalities
Name and address of employer STMicroelectronics S.r.l., Cornaredo (Italy)
Type of business or sector Semiconductors

Dates **October 1996 – March 1999**

Occupation or position held Optical-fiber Passive Components Designer
Main activities and responsibilities Optimization of the fabrication process of fusion-technology splitters and WDMs; products characterization and qualification and writing of the related technical reports
Name and address of employer OPTOTEC S.p.A., Garbagnate Milanese (Italy)
Type of business or sector Optical-fiber passive components

Dates **March – September 1995**

Occupation or position held Internship
Main activities and responsibilities Completion of the degree thesis, in order to write a paper for an international journal
Name and address of employer Electrooptics Laboratory, University of Pavia, Pavia (Italy)

Type of business or sector	University
Education and training	
Dates	October 1989 – March 1995
Title of qualification awarded	Five-year degree in Electronics Engineering, final score 105/110
Principal subjects/occupational skills covered	Optoelectronics and photonics. The subject of my degree thesis was an experimental work aimed to developing a laboratory prototype of an interferometer based on an innovative principle (induced-modulation interferometry based on the Lang-Kobayashi model)
Name and type of organisation providing education and training	Università degli Studi di Pavia, Pavia (Italy)
Personal skills and competences	
Foreign languages	
Italian	Mother tongue
English	Certified level C2(*) (advanced), full professional proficiency. Diploma in Translation into Italian <ul style="list-style-type: none"> - <i>Certificate of Proficiency in English</i>, June 2012 - <i>Diploma in Translation (DipTrans loLET)</i>, January 2013
German	Certified level C2(*) (advanced), full professional proficiency <ul style="list-style-type: none"> - <i>Goethe Zertifikat B2</i>, July 2011 - Intensive course C1, EF Internationale Sprachschule Munich, July-September 2012 - <i>Prüfung Wirtschaftsdeutsch C1</i>, November 2012 - <i>Goethe Zertifikat C1</i>, January 2013 - <i>Österreichisches Sprachdiplom C2</i>, February 2018
Spanish	Certified level C1(*) (advanced). At present not actively used <ul style="list-style-type: none"> - <i>Diploma de Español como Lengua Extranjera, Nivel C1</i>, May 2012
Russian	Certified level A2(*) (elementary). At present not actively used <ul style="list-style-type: none"> - <i>Testirovanie po Russkomu jazyku Kak Inostrannomu, Bazovyj Uroven'</i>, July 2014
	(*) Common European Framework of Reference for Languages
Social skills and competences	Good team spirit and good capability of adapting to a multicultural environment, acquired through my experience in multinational companies in my home country and abroad
Organisational skills and competences	Coordination of the component verification team (4 people), of equipment maintenance and calibration, preparation of quality audits. Managing of contacts with external suppliers in cooperation with Finance and Purchasing, coordination of the logistics, maintenance of safety measurements in the laboratory according to company policies
Technical skills and competences	Competent with the most common laboratory equipment for electronic measurements, with micro-probing stations for on-silicon measures and with the standard equipment for the localization of faults in semiconductor devices (X-Ray, IR-LIT, PEM, OBIRCH, LCT)
Computer skills and competences	Competent with MS Office™ (not including Access) and Windows 10™; independent user of MS Project™; SDL Trados™ (beginner level)
Additional information	PUBLICATIONS <ul style="list-style-type: none"> - L. Duca, L. Falzoni <i>et al.</i>: "Add-drop multiplexer a reticolo su fibra in configurazione Mach-Zehnder: studio teorico e sperimentale", presented at "Fotonica '99" workshop, Trento, Italy, June 1999 - S. Donati, L. Falzoni, S. Merlo: "A PC-Interfaced Compact Laser-Diode Feedback Interferometer for Displacement Measurements", <i>IEEE Transactions on Instrumentation and Measurement</i>, December 1996